D2684, DECEMBER 1982-REVISED JUNE 1989

- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs
- Dependable Texas Instruments Quality and Reliability

description

These devices contain two independent $J-\overline{K}$ negative-edge-triggered flip-flops. A low level at the Preset or clear inputs sets or resets the outputs regardless of the levels of the other inputs. When Preset and Clear are inactive (high), data at the J and K inputs meeting the setup time requirements are transferred to the outputs on the positive-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not directly related to the rise time of the clock pulse. Following the hold time interval, data at the J and K inputs may be changed without affecting the levels at the outputs. These versatile flip-flops can perform as toggle flip-flops by grounding K and tying J high. They also can perform as D-type flip-flops if J and \overline{K} are tied together.

The SN54HC109 is characterized for operation over the full military temperature range of $-55\,^{\circ}\text{C}$ to 125 $^{\circ}\text{C}$. The SN74HC109 is characterized for operation from $-40\,^{\circ}\text{C}$ to 85 $^{\circ}\text{C}$.

FUNCTION TABLE

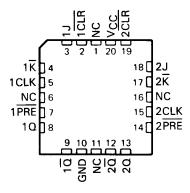
	INPUTS					
PRE	CLR	CLK	J	K	Q	Q
L	Н	Х	Х	Х	Н	٦
Н	L	X	Х	Х	L	Н
L	L	X	Χ	Х	H‡	H‡
Н	Н	†	L	L	L	Н
н	Н	†	Н	L	TOG	GLE
н	Н	†	L	н	σ_0	\overline{a}_0
Н	Н	†	Н	н	Н	L
Н	Н	L	Х	Х	a_0	\overline{a}_0

[‡]This configuration is nonstable; that is, it will not persist when Preset or Clear return to their inactive (high) level.

SN54HC109 . . . J PACKAGE SN74HC109 . . . D OR N PACKAGE (TOP VIEW)

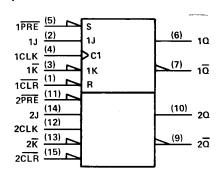
1CLR	1	U 16]Vcc
1J 🗌	2	15]2CLR
1K 🗀	3	14]]2J
1CLK	4	13] 2 <u>K</u>
1PRE	5	12]2CLK
10[6	11	2PRE
10 [7	10]20
GND [8	9]20

SN54HC109 . . . FK PACKAGE (TOP VIEW)



NC-No internal connection

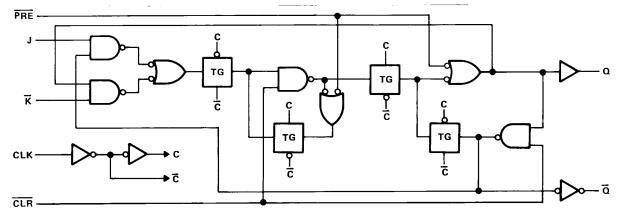
logic symbol†



[†]This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, and N packages.

logic diagram, each flip-flop (positive logic)



absolute maximum ratings over operating free-air temperature range†

Supply voltage, VCC	<i>!</i> V
Input clamp current, IJK ($V_1 < 0$ or $V_1 > V_{CC}$) ± 20 n	nΑ
Output clamp current, IOK (VO < 0 or VO > VCC ±20 n	nΑ
Continuous output current, Io (Vo = 0 to Vcc) ±25 n	nΑ
Continuous current through VCC or GND pins	nΑ
Lead temperature 1,6 mm (1/16 in) from case for 60 s: FK or J package	°C
Lead temperature 1,6 mm (1/16 in) from case for 10 s: D or N package	
Storage temperature range65 °C to 150	°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

	·	SI	SN54HC109			SN74HC109		
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
V _{CC} Supply voltage	-	2	5	6	2	5_	6	V
	V _{CC} = 2 V	1.5	_		1.5			
VIH High-level input voltage	V _{CC} = 4.5 V	3.15			3.15			V
	V _{CC} = 6 V	4.2			4.2			
	V _{CC} = 2 V	0		0.3	0		0.3	
VIL Low-level input voltage	$V_{CC} = 4.5 \text{ V}$	0		0.9	0		0.9	V
	V _{CC} = 6 V	0		1.2	0		1.2	
V _I Input voltage		0		Vcc	0		V _C C	V
VO Output voltage		0		Vcc	0		Vcc	V
	V _{CC} = 2 V	0		1000	0		1000	
tt Input transition (rise and fall) times	$V_{CC} = 4.5 V$	0		500	0		500	ns
	V _{CC} = 6 V	0		400	0		400	
T _A Operating free-air temperature		- 55		125	- 40	<u>-</u>	85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	TEST CONDITIONS		T _A = 25°C		SN54HC109		SN74HC109		UNIT	
PARAMETER	TEST CONDITIONS	VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
		2 V	1.9	1.998		1.9	,	1.9		
	$V_I = V_{IH}$ or V_{IL} , $I_{OH} = -20 \mu A$	4.5 V	4.4	4.499		4.4		4.4		
V _{OH}		6 V	5.9	5.999		5.9		5.9		V
	$V_I = V_{IH}$ or V_{IL} , $I_{OH} = -4$ mA	4.5 V	3.98	4.30		3.7		3.84		
	$V_I = V_{IH}$ or V_{IL} , $I_{OH} = -5.2$ mA	6 V	5.48	5.80		5.2		5.34		
		2 V		0.002	0.1		0.1		0.1	
	$V_I = V_{IH}$ or V_{IL} , $I_{OL} = 20 \mu A$	4.5 V		0.001	0.1		0.1		0.1	
V _{OL}		6 V		0.001	0.1		0.1		0.1	V
	$V_I = V_{IH}$ or V_{IL} , $I_{OL} = 4$ mA	4.5 V		0.17	0.26		0.4		0.33	
	$V_I = V_{IH}$ or V_{IL} , $I_{OL} = 5.2$ mA	6 V		0.15	0.26		0.4		0.33	
1	VI = VCC or 0	6 V		± 0.1	±100		± 1000	±	1000	nA
¹cc	$V_I = V_{CC} \text{ or } 0, I_O = 0$	6 V			4		80		40	μA
C ₁		2 to 6 V		3	10		10		10	pF

timing requirements over recommended operating free-air temperature range (unless otherwise noted)

				TA -	25°C	SN54	HC109	SN74HC109		UNIT
	.		vcc	MIN	MAX	MIN	MAX	MIN	MAX	
			2 V	0	6	0	4.2	0	5	
fclock	ck Clock frequency		4.5 V	0	31	0	21	0	25	MHz
			6 V	0	36	0	25	0	29	
			2 V	100		150		125		
	t _W Pulse duration	PRE or CLR low	4.5 V	20		30		25		
			6 V	17		25		21		
tw		CLK high or low	2 V	80		120		100		ns
			4.5 V	16		24		20		
			6 V	14		20		17		
		Data (J, K)	2 V	100		150		125		
			4.5 V	20		30		25		
	Setup time		6 V	17		25		21		ns
^t su	before CLK1	PRE or CLR	2 V	25		40		30	!	115
			4.5 V	5		8		6		
		inactive	6 V	4		7		5		
			2 V	0		0		0	•	
th	th Hold time, data after CLK1		4.5 V	0		0		0		ns
			6 V	0		0		0		

switching characteristics over recommended operating free-air temperature range (unless otherwise noted), $C_L = 50 \text{ pF}$ (see Note 1)

PARAMETER	FROM	то	V	TA = 25°C			SN54HC109		SN74HC109		
TANAMETER	(INPUT)	(OUTPUT)	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
			2 V	6	10		4.2		5		
fmax			4.5 V	31	50		21.		25		MHz
			6 V	36	60		25		29		
			2 V		60	230		345		290	
t _{pd}	PRE or CLR	Q or Q	4.5 V		15	46		69		58	ns
			6 V		12	39		59		49	
	-		2 V		50	175		250		220	
^t pd	CLK	Q or Q	4.5 V		15	35		50		44	ns
			6 V		12	30		42		37	
			2 V		28	75		110		95	
tŧ		Q or Q	4.5 V	1	8	15		22		19	ns
			6 V		6	13		19		16	

			_
C _{pd}	Power dissipation capacitance per flip-flop	No load, T _A = 25 °C	35 pF typ

NOTE 1: Load circuit and voltage waveforms are shown in Section 1.

IMPORTANT NOTICE

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.

Copyright © 1998, Texas Instruments Incorporated